

Sensing properties of tellurium based films to propylamine

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Abstract

The effect of propylamine ($C_{sub 3}H_{sub 7}NH_{sub 2}$) on electrical conductivity of tellurium based thin films has been investigated. It is shown that the absorption of the propylamine vapor leads to reversible increase of resistance of the layer. The sensitivity as well as response and recovery times depends on the gas concentration. The structural characterization of the films and discussion are given.

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